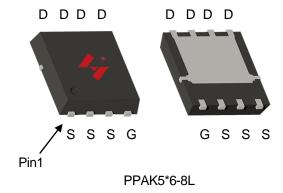


Single N-Channel Enhancement Mode MOSFET

Feature Description

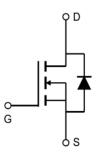
- 30V/150A $R_{DS(ON)} = 2.0 m\Omega(typ.)$ @VGS = 10V $R_{DS(ON)} = 2.7 m\Omega(typ.)$ @VGS = 4.5V
- 100% Avalanche Tested
- Reliable and Rugged
- Halogen- Free Devices Available

Pin Description



Applications

- Switching Application
- Power Management for DC/DC
- Battery Protection



N-Channel MOSFET

Ordering and Marking Information



Package Code C2: PPAK5*6-8L

Date Code Assembly Material YYXXX WW G:Halogen Free

Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plate Termi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Rat	tings (Tc=25°C Unless Otherwise Noted)			•
VDSS	Drain-Source Voltage		30	V
Vgss	Gate-Source Voltage		±20	V
TJ	Maximum Junction Temperature		150	°C
Tstg	Storage Temperature Range		-55 to 150	°C
ls	Source Current-Continuous(Body Diode) Tc=25°C		150	А
Mounted on I	Large Heat Sink			
IDM	Pulsed Drain Current *	Tc=25°C	540	А
	Continuos Prois Consul	Tc=25°C	150	А
lσ	Continuous Drain Current	Tc=100°C	94	А
Po		Tc=25°C	156	W
	Maximum Power Dissipation	Tc=100°C	62.5	W
R ₀ JC	Thermal Resistance, Junction-to-Case		0.8	°C/W
R _{eJA}	Thermal Resistance, Junction-to-Ambient **		40	°C/W
Eas	SinglePulsed-Avalanche Energy ***	L=0.1mH	378.5	mJ

Note: * Repetitive rating; pulse width limited by max.junction temperature.

Electrical Characteristics(Tc =25°C Unless Otherwise Noted)

Cumbal	Davamatar	Test Conditions		HY3503		I I to i 4	
Symbol	Parameter	rest Conditions	Min	Тур.	Max	Unit	
Static Char	Static Characteristics						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =250μA	30	-	-	V	
Ipss	Danie de Course l'acteure Course	V _{DS} =30V,V _{GS} =0V	-	-	1	μA	
IDSS	Drain-to-Source Leakage Current	TJ=125°C	-	-	50	μA	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	1	2	3	V	
Igss	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	±100	nA	
Decirit Course On State Resistance		V _{GS} =10V,I _{DS} =20A	-	2.0	2.5		
Rds(on)*	Drain-Source On-State Resistance	V _{GS} =4.5V,I _{DS} =20A	-	2.7	3.4	mΩ	
Diode Characteristics							
V _{SD} *	Diode Forward Voltage	I _{SD} =20A,V _{GS} =0V	-	0.8	1.0	V	
trr	Reverse Recovery Time	la==20.4 dla=/dt=100.4/ua	-	28	-	ns	
Qrr	Reverse Recovery Charge	Isp=20A,dIsp/dt=100A/µs	-	71	-	nC	

^{**} Surface mounted on FR-4 board.

^{***} Limited by TJmax , starting TJ=25°C, L = 0.1mH, RG= 25Ω , VGS =10V.



Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Cumbal	Dorometer	Toot Conditions	Test Conditions HY35	HY3503		l lmi4
Symbol	Symbol Parameter Test Condition		Min	Тур.	ур. Мах	Unit
Dynamic (Dynamic Characteristics					
Rg	Gate Resistance	V_{GS} =0V, V_{DS} =0V,F=1 MHz	-	0.55	-	Ω
Ciss	Input Capacitance	V _{GS} =0V,	-	4900	-	
Coss	Output Capacitance	V _{DS} =25V,	-	541	-	pF
Crss	Reverse Transfer Capacitance	Frequency=1.0MHz	-	153	-	
td(ON)	Turn-on Delay Time		-	25	-	
Tr	Turn-on Rise Time	V _{DD} =15V,R _G =3.3Ω,	-	90	-	200
td(OFF)	Turn-off Delay Time	lps=20A,Vgs=10V	-	50	-	ns
Tf	Turn-off Fall Time		-	40	-	
Gate Charge Characteristics						
Qg	Total Gate Charge	\/ -24\/ \/ -10\/	-	100	-	
Qgs	Gate-Source Charge	$V_{DS} = 24V, V_{GS} = 10V,$ $I_{D} = 20A$	-	14	-	nC
Qgd	Gate-Drain Charge	ID-20A	-	28	-	

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

Figure 1: Power Dissipation

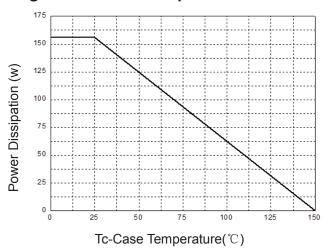


Figure 3: Safe Operation Area

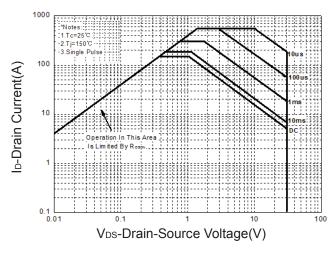


Figure 5: Output Characteristics

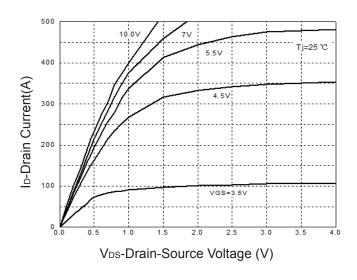


Figure 2: Drain Current

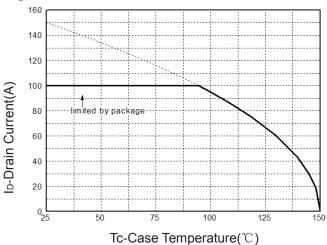


Figure 4: Thermal Transient Impedance

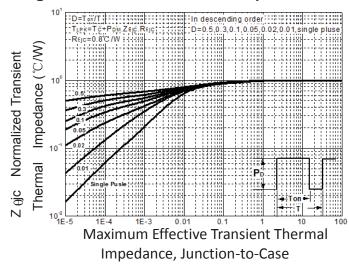
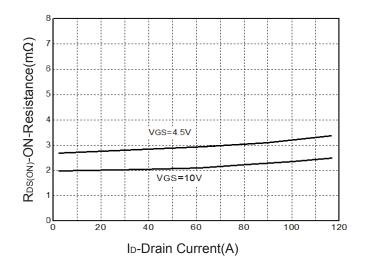


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

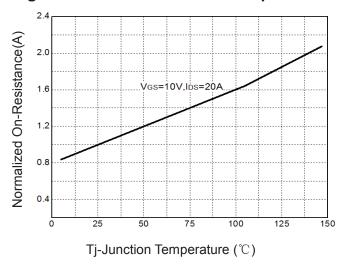


Figure 9: Capacitance Characteristics

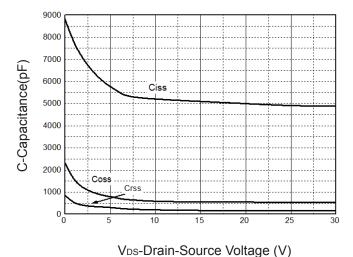


Figure 8: Source-Drain Diode Forward

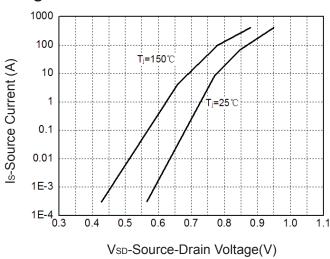
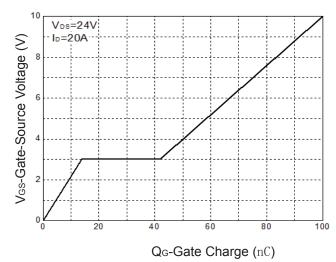
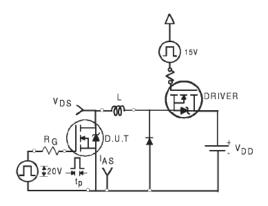


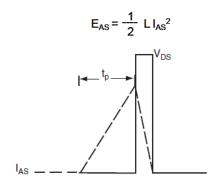
Figure 10: Gate Charge Characteristics



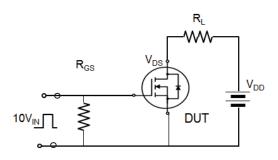


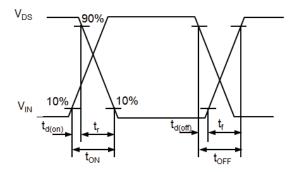
Avalanche Test Circuit



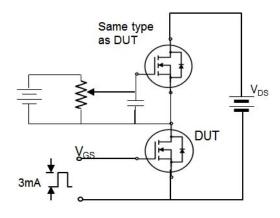


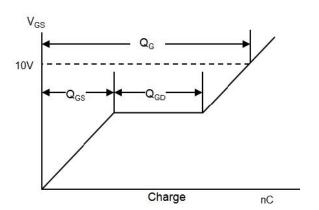
Switching Time Test Circuit





Gate Charge Test Circuit





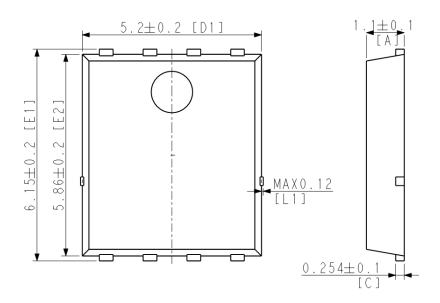


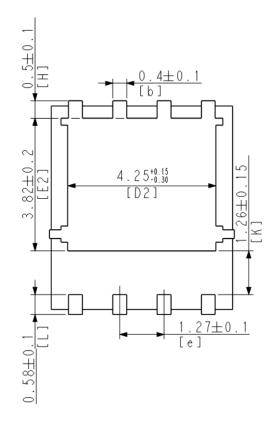
Device Per Unit

Package Type	Unit	Quantity
PPAK5*6-8L	Reel	5000

Package Information

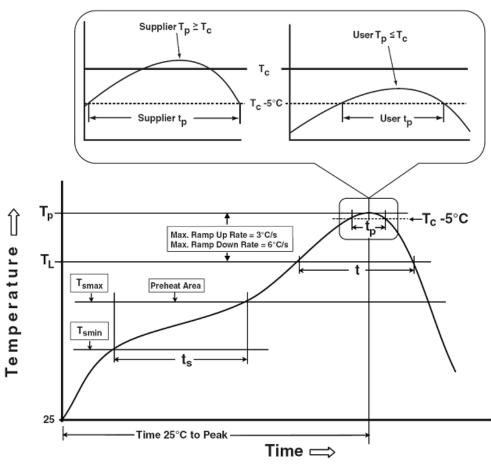
PPAK5*6-8L







Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly		
Preheat & Soak	100 °C	150 °C		
Temperature min (T _{smin})	150 °C	200 °C		
Temperature max (T _{smax})	60-120 seconds	60-120 seconds		
Time (Tsmin to Tsmax) (t₅)	00-120 Seconds	60-120 Seconds		
Average ramp-up rate	3 °C/second may	3°C/second max.		
(T _{smax} to T _P)	3 °C/second max.			
Liquidous temperature (T₋)	183 °C	217 °C		
Time at liquidous (t∟)	60-150 seconds	60-150 seconds		
Peak package body Temperature	See Classification Temp in table 1	SeeClassification Tempin table 2		
(T _p)*	See Classification Temp in table 1			
Time (t _P)** within 5°C of the specified	20** seconds	30** seconds		
classification temperature (T₀)	20 seconds			
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.		
Time 25°C to peak temperature	6 minutes max.	8 minutes max.		
+T-decree for a slowerfly T-very state (T-) is defined as a small continuous and a second continuous				

^{*}Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (tp) is defined as a supplier minimum and a user maximum.

HY3503C2



Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm ³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168 Hrs /500 Hrs /1000 Hrs, Bias @ 150℃
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121℃
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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